

Oct. 23, 2007



FOR IMMEDIATE RELEASE

OPTIMALTEST DEMONSTRATES LATEST TEST MANAGEMENT CAPABILITIES, HOSTS IN-BOOTH PRESENTATIONS ON TEST ISSUES AT ITC

. . . company is also Diamond-level corporate supporter of International Test Conference

International Test Conference, Santa Clara, California, Oct. 23, 2007 – OptimalTest, the leader in providing innovative, integrated enterprise-wide test management solutions, is an exhibitor at the 38th annual International Test Conference at the Santa Clara Convention Center, Oct. 23-25, as well as a Diamond-level corporate supporter of the conference.

At ITC, OptimalTest is demonstrating the latest capabilities of its Test Management Solutions (TMS) suite of software, OT-Reports and Outlier Management.

OT-Reports is an expert system that goes beyond simple report generation. It identifies problems in the test process or on the test floor at any point from initial test to post production and also recommends specific corrective action for more rapid problem-solving and greater efficiency. The Outlier Management capability of OptimalTest's Test Management Solutions (OT-TMS) draws on a unique array of quality management solutions for a comprehensive automated approach to manage – not just detect – outliers. A rich variety of outlier detection methods – among them Static Parts Average Testing (PAT), Real-time PAT, WECO PAT, Dynamic Stressing, ULPY and Data Integrity – incorporated into customizable families of rules gives OT-TMS capabilities that are unique to the industry and provide more complete outlier management for the highest level of end-product quality.

OptimalTest Demonstrates Latest Test Management Capabilities

As part of its ITC exhibit, OptimalTest is also highlighting the benefits of OT-TMS to Fabless semiconductor companies, and explaining how OT-TMS addresses the challenges of their unique business model.

In addition, at regular intervals within its booth (No. 518), OptimalTest will feature industry experts giving public presentations on today's test challenges (see attached presentation schedule).

Among OptimalTest's speakers are John Bearden, formerly with IBM; Bob Madge, and Bill Price.

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About OptimalTest

Established in 2005, OptimalTest provides integrated, comprehensive, universal test management solutions software for the entire test process. The company is committed to helping test and semiconductor professionals master test management through its solutions software to achieve unprecedented ROI on their technology assets and to lower test cost of ownership. A privately held company whose founders are seasoned industry executives, OptimalTest is growing globally and has worldwide operations in Asia/Pacific, Europe and the United States. For more information, go to www.optimaltest.com.

Editors, for more information, contact:
Barbara Palmer
Palmer Communications
914 725 8057
bpalmer@palmercommunications.com